

## RELIABILITY DATA

**LT1187 / 1189 / 1190 / 1191 / 1192 / 1193 / 1194 / 1195**

**8/21/2006**

**• OPERATING LIFE TEST**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS <sup>(1)</sup> AT +125°C	NUMBER OF FAILURES <sup>(2)</sup>
CERDIP	558	9130	0129	561.47	0
PLASTIC DIP	6,726	9130	0524	7,839.83	0
SOIC/SOT/MSOP	578	9308	9850	864.73	0
	7,862			9,266.03	0

**• HIGHLY ACCELERATED STRESS TEST AT +131°C/85%RH**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS <sup>(4)</sup> AT +85°C	NUMBER OF FAILURES
PLASTIC DIP	292	9443	9703	519.56	0
SOIC/SOT/MSOP	299	9902	0101	287.04	0
	591			806.60	0

**• PRESSURE COOKER TEST AT 15 PSIG, +121°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
PLASTIC DIP	7,673	9225	0041	457.13	0
SOIC/SOT/MSOP	4,649	9217	0501	462.00	0
	12,322			919.13	0

**• TEMP CYCLE FROM -65°C to +150°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
CERDIP	17	0129	0129	1.70	0
PLASTIC DIP	542	9302	9810	238.91	0
SOIC/SOT/MSOP	1,035	9250	0122	493.46	0
	1,594			734.07	0

**• THERMAL SHOCK FROM -65°C to +150°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
CERDIP	17	0129	0129	0.26	0
PLASTIC DIP	304	9443	9810	103.40	0
SOIC/SOT/MSOP	775	9217	0004	224.06	0
	1,096			327.71	0

(1) Assumes Activation Energy = 1.0 Electron Volts  
 (2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 0.20 FITS  
 (3) Mean Time Between Failures in Years = 570,386  
 (4) Assumes 20X Acceleration from 85°C to +131°C  
 Note: 1 FIT = 1 Failure in One Billion Hours.